



## DESCRIPTION

The MXN3349 uses advanced trench technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

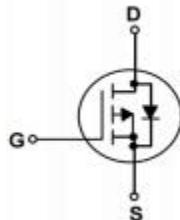
## GENERAL FEATURES

- $V_{DS}=-30V$ ,  $I_D=-50A$   
 $R_{DS(ON)}(\text{Typ.})=5.8m\Omega$  @  $V_{GS}=-10V$   
 $R_{DS(ON)}(\text{Typ.})=8m\Omega$  @  $V_{GS}=-4.5V$
- Advanced High Cell Density Trench Technology
- Low Gate Charge
- 100% EAS Guaranteed
- Green Device Available

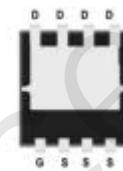
## APPLICATION

- Power Management Switches
- Battery Protection Application

## PINOUT



Schematic diagram



DNF3x3 top and bottom view

## ORDERING INFORMATION

Part Number	Storage Temperature	Package	Devices Per Reel
MXN3349	-55°C to 150°C	DFN3x3	5000

## ABSOLUTE MAXIMUM RATINGS ( $T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous( $T_C=25^\circ C$ )	$I_D$	-50	A
Drain Current-Continuous( $T_C=100^\circ C$ )	$I_D$	-32	A
Pulsed Drain Current <sup>(Note1)</sup>	$I_{DM}$	-200	A
Single Pulse Avalanche Energy <sup>(Note2)</sup>	$E_{AS}$	80	mJ
Total Power Dissipation( $T_C=25^\circ C$ )	$P_D$	69	W
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C
Thermal Resistance, Junction-to-Ambient <sup>(Note3)</sup>	$R_{\theta JA}$	65	°C/W
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.8	°C/W

Note 1. Pulse width limited by maximum junction temperature  $T_{J(MAX)}=150^\circ C$

Note 2. The EAS data shows Max. rating. The test condition is  $V_{DD}=-25V$ ,  $V_{GS}=-10V$ ,  $L=0.1mH$ ,  $I_{AS}=-40A$ .

Note 3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.



**ELECTRICAL CHARACTERISTICS**( $T_J=25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	$\mu\text{A}$
		$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}, T_J=100^\circ\text{C}$	-	-	-100	$\mu\text{A}$
Gate-Body Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1.0	-	-2.5	V
Drain-Source On-State Resistance <sup>(Note1)</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-20\text{A}$	-	5.8	8	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-15\text{A}$	-	8	13.5	$\text{m}\Omega$
Forward Transconductance <sup>(Note1)</sup>	$g_{\text{FS}}$	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-20\text{A}$	-	50	-	S
<b>Dynamic Characteristics</b> <sup>(Note2)</sup>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=-15\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	3512	-	pF
Output Capacitance	$C_{\text{oss}}$		-	463	-	pF
Reverse Transfer Capacitance	$C_{\text{rss}}$		-	369	-	pF
Gate Resistance	$R_g$	$F=1.0\text{MHz}$	-	9.3	-	$\Omega$
<b>Switching Characteristics</b> <sup>(Note2)</sup>						
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=-15\text{V}, I_{\text{D}}=-20\text{A}, V_{\text{GS}}=-10\text{V}, R_{\text{G}}=3\Omega$	-	10.8	-	nS
Turn-on Rise Time	$t_r$		-	13.2	-	nS
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$		-	73	-	nS
Turn-Off Fall Time	$t_f$		-	35	-	nS
Total Gate Charge	$Q_g$	$V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-20\text{A}, V_{\text{GS}}=-10\text{V}$	-	34	-	nC
Gate-Source Charge	$Q_{\text{gs}}$		-	9.9	-	nC
Gate-Drain Charge	$Q_{\text{gd}}$		-	10.4	-	nC

**Drain-Source Diode Characteristics**

Diode Forward Voltage <sup>(Note1)</sup>	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{s}}=-1\text{A}$	-	-	-1.2	V
Continuous Source Current( $T_c=25^\circ\text{C}$ )	$I_{\text{SD}}$	-	-	-	-50	A
Reverse Recovery Time	$t_{\text{rr}}$	$I_{\text{F}}=-20\text{A}, \frac{dI}{dt}=100\text{A}/\mu\text{s}$	-	25	-	nS
Reverse Recovery Charge	$Q_{\text{rr}}$		-	10	-	nC

Note 1. The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .

Note 2. This value is guaranteed by design hence it is not included in the production test.



## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1. Output Characteristics

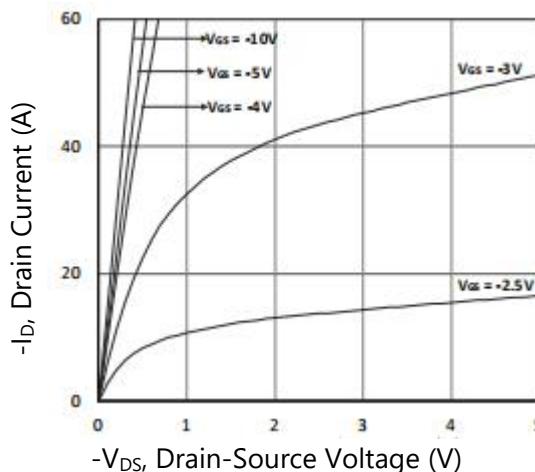


Figure 2. Transfer Characteristics

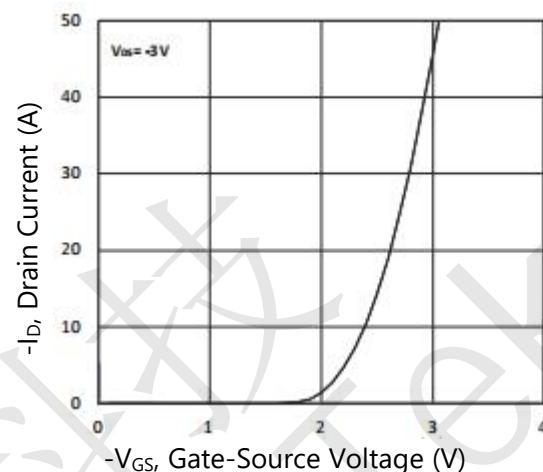


Figure 3. Normalized  $R_{DS(ON)}$  vs Temperature

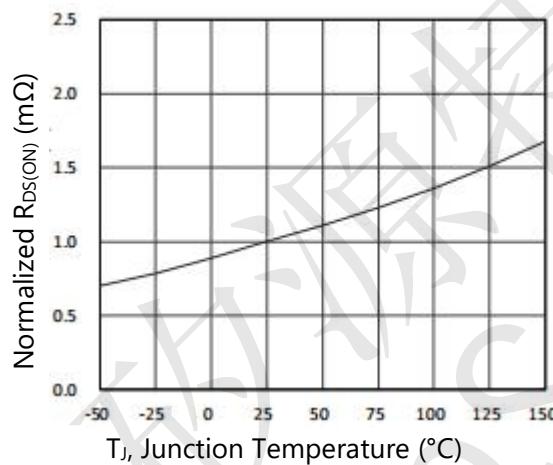


Figure 4.  $R_{DS(ON)}$  vs  $V_{GS}$

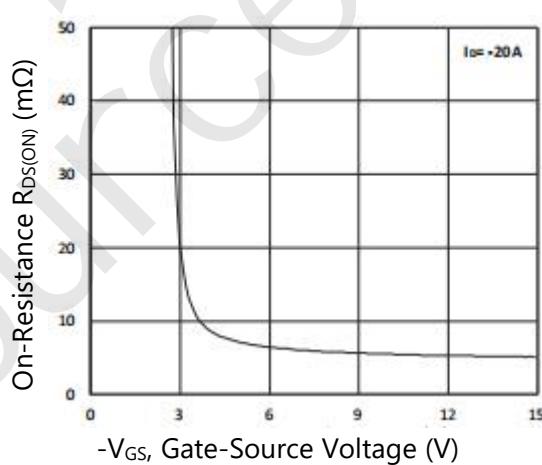


Figure 5.  $R_{DS(ON)}$  vs  $I_D$

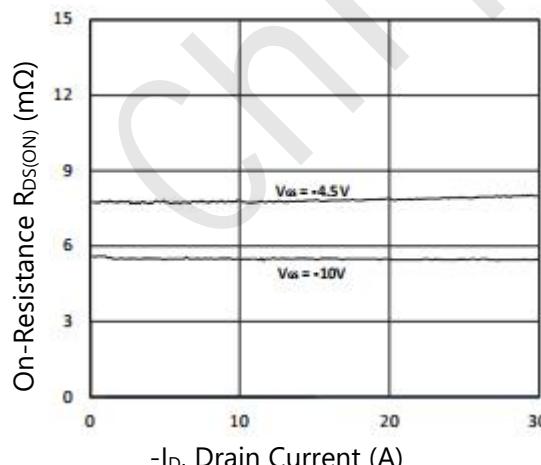
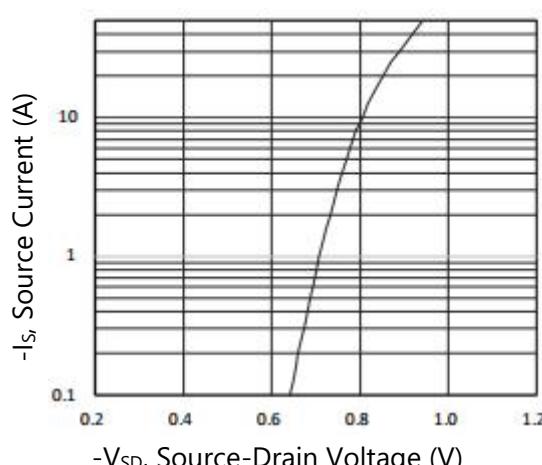


Figure 6. Forward Characteristics of Reverse





## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7. Capacitance Characteristics

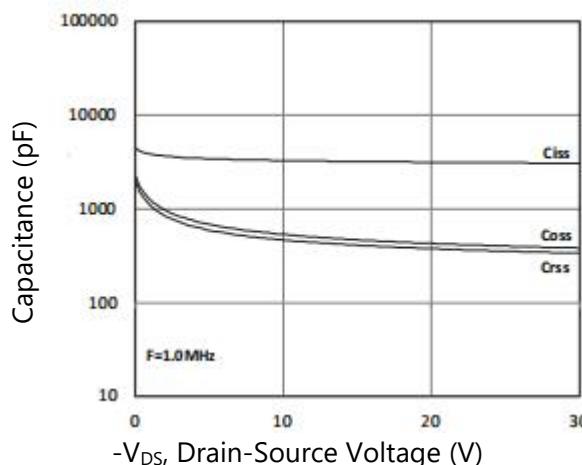


Figure 8. Safe Operating Area

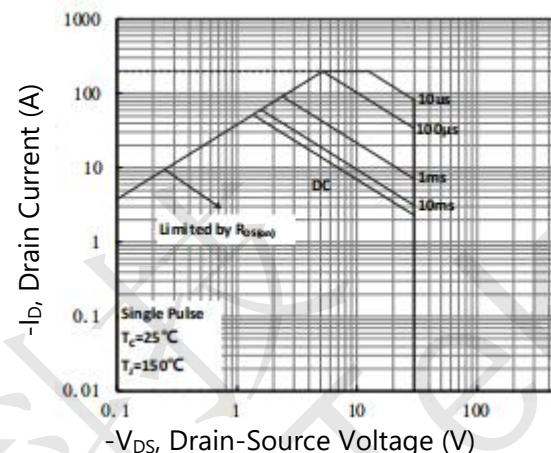


Figure 9. Transfer Characteristics

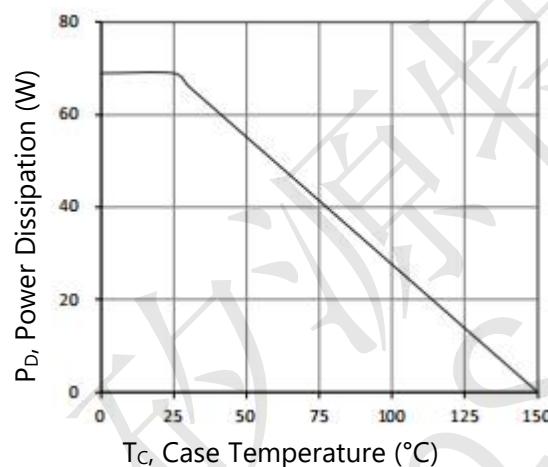


Figure 10. Normalized Threshold Voltage

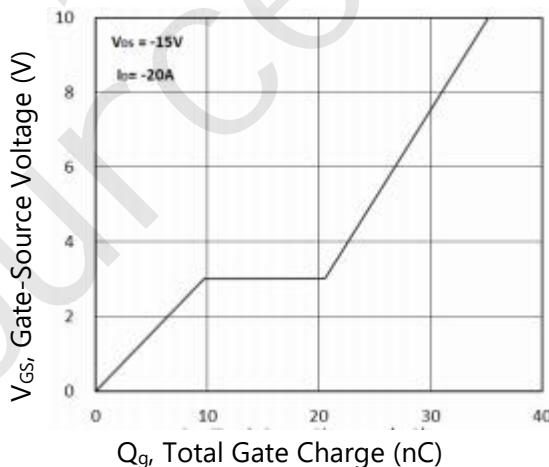
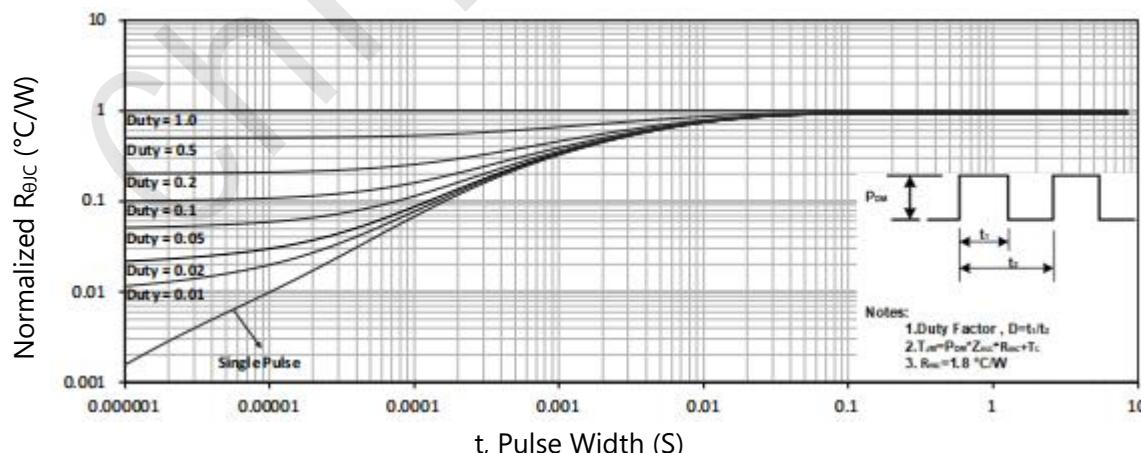


Figure 11. Normalized Maximum Transient Thermal Impedance





TEST CIRCUIT

Figure 1. Gate Charge Test Circuit & Waveforms

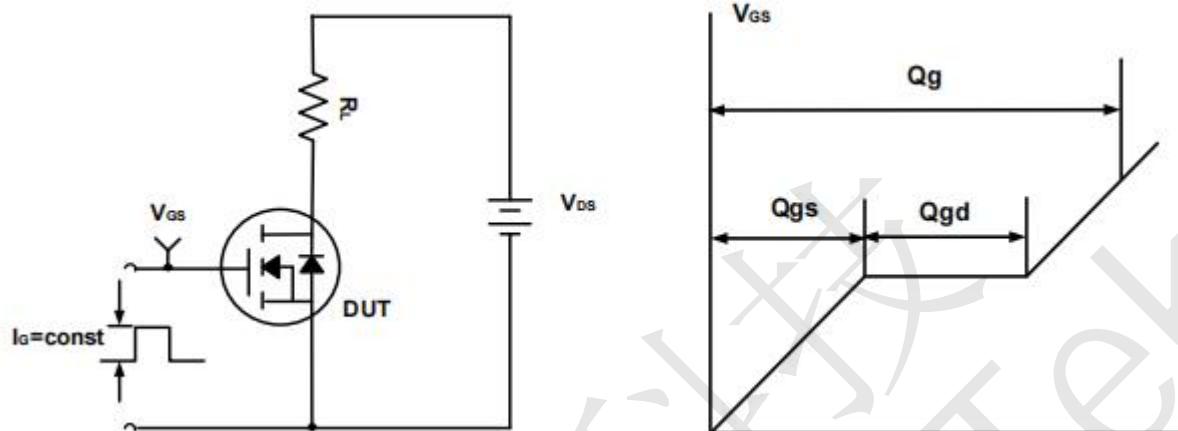


Figure 2. Switching Test Circuit & Waveforms

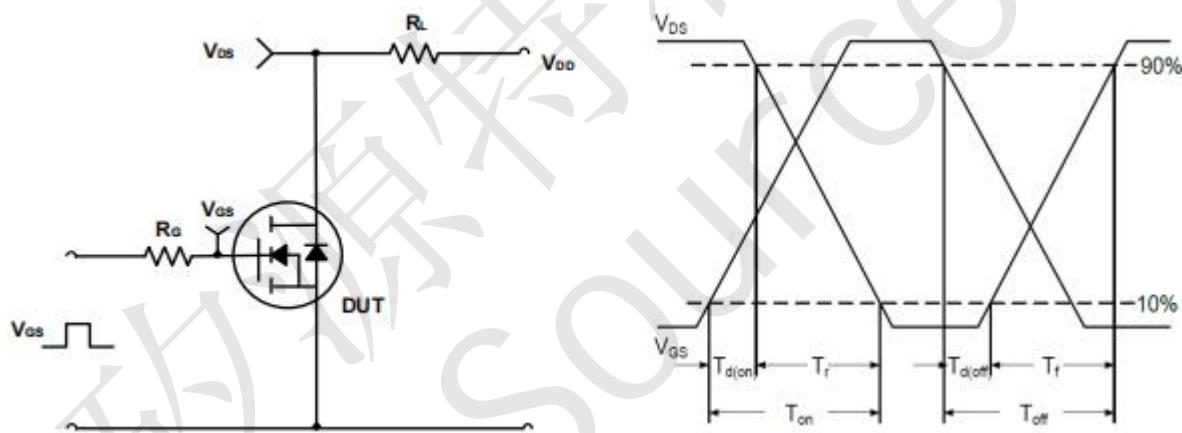
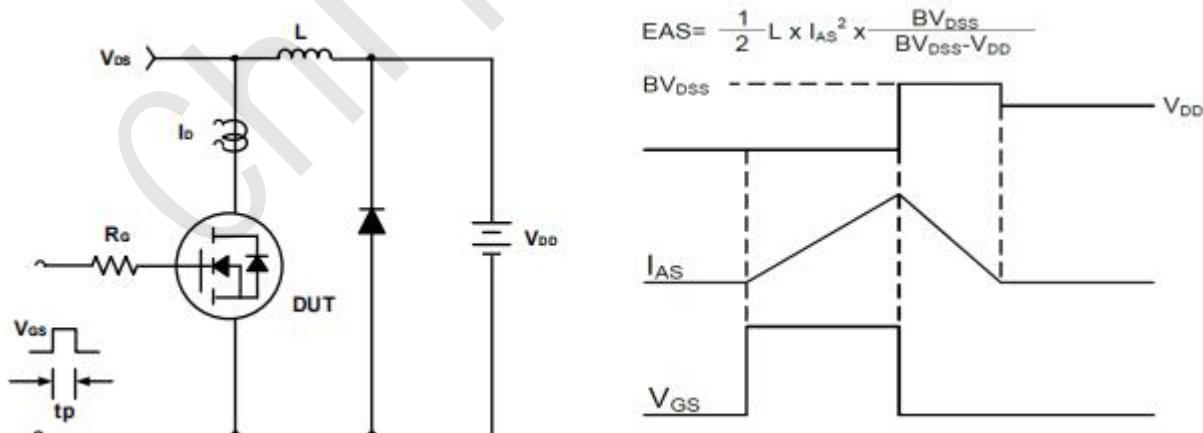


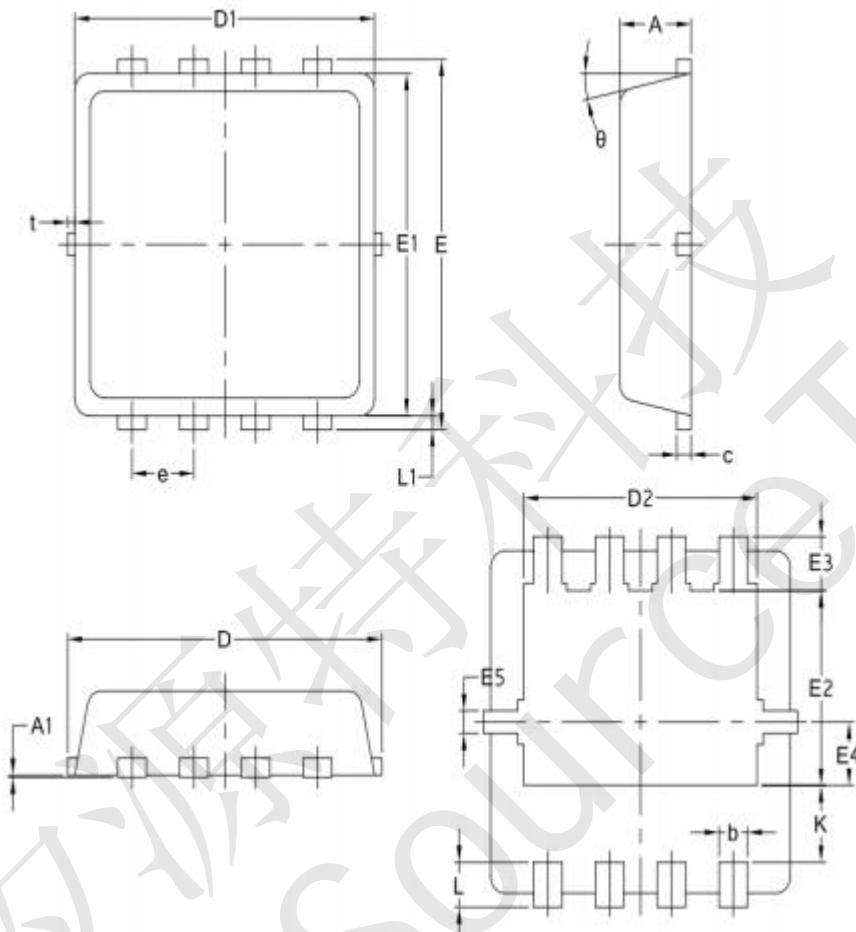
Figure 3. Unclamped Inductive Switching Circuit & Waveforms





## PACKAGE INFORMATION

DFN3x3-8L



Symbol	Dimensions In Millimeters			Symbol	Dimensions In Millimeters		
	MIN.	NOM.	MAX.		MIN.	NOM.	MAX.
A	0.70	0.75	0.85	E3	0.28	0.48	0.65
A1	-	-	0.05	E4	0.37	0.57	0.77
b	0.20	0.30	0.40	E5	0.10	0.20	0.30
c	0.10	0.152	0.25	e	0.60	0.65	0.70
D	3.15	3.30	3.45	K	0.59	0.69	0.89
D1	3.00	3.15	3.25	L	0.30	0.40	0.50
D2	2.29	2.45	2.65	L1	0.06	0.125	0.20
E	3.15	3.30	3.45	t	0	0.075	0.13
E1	2.90	3.05	3.20	θ	10°	12°	14°
E2	1.54	1.74	1.94				